Fall 2015

University of Illinois at Urbana-Champaign

ELECTRICAL AND COMPUTER ENGINEERING 340

Semiconductor Electronics

The course director is Prof. John Dallesasse

The course structure consists of three lecture/discussion meetings per week. Final course grades are based on the distribution of total points accumulated on the final exam, two hour-long exams, three in-class quizzes, and assigned homework, as described in the section on grading criteria.

The Course information listed below is included on the pages, which follow:

General information	1
Purpose of the Course	2
Instructors and TA Office Hours	
Required and Reference Textbooks	
Course Expectations	5
Homework Guidelines and Format	
Exams	7
Grading Criteria	7
Course Policy on Absences	
Course Schedule and Outline	

Prerequisite: <u>Physics 214</u> and credit or concurrent registration in <u>ECE 329</u>. Graduate credit not allowed toward degrees in electrical and computer engineering.

3 HOURS.

Purpose of the Course

The purpose of this course is to provide the student with the essential background on semiconductor materials and a basic understanding of the following semiconductor electronic devices that will be required for a successful career in electrical engineering:

> p-n Junctions Light-Emitting Diodes/Photodetectors Bipolar Junction Transistors Field Effect Transistors

These topics are important to the professional electrical or computer engineer because these devices are utilized in almost every area of electrical or computer engineering. To be productive and remain employed throughout a 40+ year career in electrical or computer engineering, the electrical and computer engineer needs to understand the fundamentals of semiconductors and the operation and limitations of these devices. A successful engineer will be able to apply this knowledge in the different areas of electrical engineering, whether he or she works directly in circuits and system design, control systems, communications, computers, electromagnetic fields, bioengineering, power systems, directly in the semiconductor industry, or in areas yet to develop that will certainly rely heavily on semiconductor devices and/or integrated circuits.

The material in this course will provide the background that will give the student the ability to learn and understand the performance and limits of improved devices that will be required throughout your electrical or computer engineering career.

ECE 340 Instructor, TAs and Office Hours

Course Director: Professor John Dallesasse

2114 Micro and Nanotechnology Laboratory

333-8416

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Fall 2015 ECE 340 Instructors:

	Section	Time	Location	Office Hours	Tel.#	Email
				Location		
Prof. M. Feng	A	2:00	2015 ECEB	2016 MNTL	333-8080	mfeng@
Prof. W. Zhu	В	10:00	2015 ECEB	3258 MNTL	244-9456	wjzhu@
Prof. K. Kim	D	11:00	2015 ECEB	2048 ECEB	333-7162	kevinkim@
Prof. C. Bayram	E	1:00	2015 ECEB	3264 MNTL	300-0987	cbayram@
Prof. J. Dallesasse	X	12:00	2015 ECEB	2014 MNTL	333-8416	jdallesa@
TA: Ben Kesler			3034 MNTL	2036 ECEB	333-4214	bkesler2@
TA: Tommy O'Brien			3034 MNTL	2036 ECEB	333-4214	tobrien3@
TA: John Carlson			3034 MNTL	2036 ECEB	333-4214	jcarls21@
TA: Ardy Winoto			1225 MNTL	2036 ECEB		winoto2@
TA: Junyi Qiu			1225 MNTL	2036 ECEB		qiu12@

Room 2120 ECEB is the office for registration, section changes, lost & found.

ECE 340 - INSTRUCTOR AND TA OFFICE HOUR SCHEDULE						
TIME		MONDAY	TUESDAY	WEDNESDAY	THURSDAY	FRIDAY
8 – 9						
9 - 10						
10 - 11						
11 - 12						
12 - 1					TA: B. Kesler	
1 – 2					TA: T. O'Brien	
2 – 3			C. Bayram		TA: J. Qui	
3 – 4			K. Kim	J. Dallesasse		
4 – 5			W. Zhu	M. Feng	TA: A. Winoto	
5 – 6						
6 – 7					TA: J. Carlson	

Office hours will be held as listed, in the offices given in the table. You can make individual appointments to see (any of the) instructors at times other than the scheduled office hours.

Required Textbook:

Solid State Electronic Devices Ben G. Streetman and Sanjay Banerjee, **Seventh** Edition Prentice Hall, 2000/2006

Reference Textbooks are Available in Grainger Engineering Library:

Semiconductor Device Fundamentals Pierret, Robert F. Addison-Wesley, 1996

Call No: 621.3817M91D1986 Author: Muller, R.S./Kamins, T.I.

Title: Device Electronics for Integrated Circuits, 2nd ed.

Call No: 621.381sa19f Author: Sah, Chih-Tang

Title: Fundamentals of Solid-State Electronics

Call No: 621.38152si64s Authors: Singh, Jasprit

Title: Semiconductor Devices, An Introduction

Call No: 621.38152P615s1989

Authors: Pierret, Robert F./Neudeck, G.W.

Title: Modular Series on Solid State Devices, Volumes 1-4

Call No: 537.622N26S Authors: Neamen, Donald A.

Title: Semiconductor Physics and Devices

Modern Semiconductor Devices for Integrated Circuits Chenming C. Hu 2009, First Edition, 384 pages (not yet in Grainger)

Free online textbook, see: http://ecee.colorado.edu/~bart/book/contents.htm

By Prof. Bart Van Zeghbroeck at the University of Colorado

Requirements of the Course

<u>Class etiquette:</u> Students must study the assigned material before class, attend class regularly, be attentive, ask questions, and complete the required work satisfactorily. <u>NO ELECTRONIC DEVICES</u> are allowed in class. Electronic devices can be a source of distraction to you and for the fellow students around you so please be respectful by not using them in class.

Homework: The homework will consist of several types of problems: There will be a few simple "plug-in" problems to illustrate and reinforce the concepts covered in the assigned reading and lectures, and derivations of equations given in the textbook or in class. Another type of problem that is important in developing the understanding of semiconductor devices and their applications is the application or extension of the concepts that have been studied to new situations. Occasionally, a problem will be assigned on topics that are not studied in class. This type of problem is probably the most important because it teaches the student how to learn new material on his own, an ability that will be essential for a successful career in electrical or computer engineering. Another type of problem that will be assigned on certain topics is the design problem, where judgment must be used and there may be a number of acceptable answers. The final type of problem is the computer-based problem in which the variation of a particular quantity can be plotted as a function of some variable for different parameters. Examples are the variation of the free electron concentration in a semiconductor sample as a function of temperature for different values of the doping concentrations, N_d and N_a, and the characteristics of a field effect transistor where the drain current is plotted as a function of the drain voltage for different values of the gate voltage. These types of problems are tedious to analyze using a simple calculator, but are trivial using a computer and plotting routines.

If the student has not already acquired the ability to write simple computer programs and produce computer generated graphs using Mathematica, Excel, Matlab, MathCAD, or some other program, this ability should be acquired in the first four weeks of the course.

The homework will be <u>assigned on Friday</u> and must be turned in <u>at the beginning</u> of the next Friday class, unless otherwise specified. <u>Late homework will NOT be accepted</u>.

Homework guidelines:

Homework must be done on $8-1/2 \times 11$ paper, preferably on engineer calculation sheets or engineering calculation pads. The pages for each homework assignment <u>must be stapled together</u>. The pages must be numbered, and the following information must be on the first page: (1) your name, (2) Net ID #, (3) assignment number, date, (4) class section, and (5) instructor's name.

The homework must be neat and easily readable, in pen, dark pencil, or computer output, and all work leading to your answer must be shown. HW done on paper ripped from a spiral-bound notebook (with rough edges) will incur a penalty.

Homework format: The solution to each homework or exam problem *must* include all of the following that are appropriate for the particular problem:

- A diagram and/or the equations required for the problem.
- Solution of the equations for the appropriate quantities, using only variable symbols.
- In the final expression, numbers <u>and units</u> must be substituted. Note: <u>units for each physical quantity in the equation must be *explicitly* included.</u>

The units of the quantity in the final answer must be converted to those desired by using unity multiplication factors. The units commonly used in semiconductor device work are those in the SI system of units, with the exception that it is common to use cm (10^{-2} m) or sometimes μ m (10^{-6} m), instead of meters for length measurements, and cm³ rather than m³ for volume measurements.

Finally, and only after all of the above have been done, use a calculator to complete the necessary numerical calculations, and then **draw a box around your answer.**

<u>Significant Figures:</u> In the calculation of quantities from theoretical models or from experimental measurements, it is important to be aware of in the number of significant figures that are meaningful in your final result:

- (1) If an expression involves the product or quotient of several quantities, the number of significant figures retained in the answer should only be as many as the number of significant figures in the least precise quantity used in the calculation,
- (2) If a calculation involves sums and differences, the number of significant figures retained should be determined by the smallest number of decimal places in any term in the expression: e.g., 12.5 + 1.3295 = 13.8.
- (3) For calculations in this course, assume that the quantities given are sufficiently accurate to justify retaining three significant figures in your final result. Display your results in the form of a graph whenever appropriate.

You will not receive **full** credit for a homework or exam problem unless all of these requirements are complied with. If we cannot read your work on the homework or exams, you will receive zero credit!

You are encouraged to work together and discuss the homework assignments. Please see the professors and/or the TAs during their office hours for assistance on material or homework problems that you do not understand. If you are having difficulty with a particular topic, try reading about the same topics in the books that are available for ECE 340 in the Grainger Engineering Library (See the list on page 4). However, the homework assignments that you turn in must be your own work and not copied from someone else's solutions. (Copying someone else's solution and submitting it as your own is cheating!)

Note!

Homework or exam problems that are illegible or difficult to read and follow, or do not include the appropriate units explicitly, will not receive full credit.

Be neat!

Quizzes, Exams, and Grading

Quizzes: There will be three short in-class quizzes that will not be announced in advance. Each quiz may consist of a few conceptual questions and will take about 10-15 minutes. The purpose of studying homework problems diligently is to help you keep up the pace and quizzes are designed to gauge your progress. You should use the quizzes as a diagnostic measure to identify and strengthen your possible weak points on the material.

Midterms & Final: In addition to quizzes, there will be two hourly exams and a comprehensive final exam. Both hourly and final exams will consist of several problems or questions. The exams will be closed book, and no calculator is allowed. An equation sheet and the physical parameters and constants that are required in the solutions will be provided with the exam, not before. The hourly exams are given in the evening at the dates and times shown in the syllabus. They will take one hour. The format of your exam solutions should be the same as that used for the homework assignments: units must be shown explicitly, your answer must be circled and your work must be readable. Numerical answers should contain three significant figures unless more are justified by the given data. The final exam is a three hour combined exam, which will be given at a time to be scheduled. You will need a scientific calculator for the homework.

Hour Exam I: Thursday, October 8th
Hour Exam II: Thursday, November 5th

Final Exam: To Be Announced

<u>Grading Criteria:</u> Your grade in ECE 340 is based primarily on your scores on the reading checks, homework assignments, quizzes, one hour-exam, final exam, and your class participation as follows:

Final Score = Homework + Quizzes + Midterm + Final Exam score as follows:

Letter grades will be assigned to different ranges of the Final Scores at a meeting of the course staff at the end of the semester. Plus and minus grades may be given to the highest and lowest 1/3 in each letter grade range.

Study the material ahead of time, attend class, pay attention and ask questions! Your performance and contributions in class will help you learn the material. Because of this grading procedure, it is not possible to accurately determine your letter grade from your scores before the course is completed. As a guide, the grade distributions for the last semesters are given below:

Fall 2012:	22% A's	34% B's	28% C's	12% D's	4% F's
Spring 2013:	25% A's	31% B's	33% C's	9% D's	2% F's
Fall 2013:	27% A's	35% B's	24%C's	8% D's	6% F's

From this grade distribution, you can make a rough estimate how you are doing throughout the semester by obtaining your percentile ranking from the TAs. Any questions regarding course grading should be addressed to Professor J. Dallesasse.

The topics covered in this course build on each other, so what you learn early in the course will be needed to understand later topics. Therefore, keep up with the schedule, study the daily assignments, do the homework, and don't get behind. The material for this course is covered in a number of textbooks listed on page 4 that are available in the Engineering Library. If a subject is not understood clearly try another book or attend office hours. Be resourceful!

Course Policy on Absences

If you miss a quiz, exam, or homework assignment the following procedures apply:

- 1) Absences for job interviews or for specific university-sponsored events must be pre-arranged with the course director, Prof. Dallesasse. Pre-arranged excused absences will not be given for homework assignments you must turn in your homework or arrange to have it turned in for you prior to your absence. Pre-arranged excused absences will not be given for exams except in the case of specific university-related events.
- 2) In the event of illness, you must receive an Excused Absence Form from the Undergraduate College Office, Room 207 Engineering Hall, indicating what work you have missed and the reason for the absence. This form must be signed by a physician or medical official for a medical excuse, or by the Office of the Dean of Students (Emergency Dean) for a personal excuse due to personal illness, family emergencies, or other uncontrollable circumstances. The office may be reached at 333-0050. Note that Excused Absence Forms in the case of illness are now only given out by the office for the case of serious illness lasting more than 3 days.

For missed classes or hour exams, present the completed form in person to the course director Prof. Dallesasse and your instructor as possible after you return.

Scores on quizzes and hour exams missed due to excused absences will not be made up. Your grade will be determined based on the average of the grades that you have completed. Specifically, the average of your completed scores will be used to determine the total, homework or hour exam score and the final total score.

Work missed due to an unexcused absence will be counted as a 0.

You <u>must</u> take the final exam to receive a grade for the course. If you miss the final exam for a legitimate reason, you will automatically receive a final course grade of INCOMPLETE. In this case to complete the course, you must make arrangements through your Dean's office and with the instructor to take a makeup final exam that will be given at the scheduled time at the end of the following semester. An unexcused absence from the final will result in a grade of "0" on the final.

Students with Disabilities

Students with disabilities who may qualify for extra time while taking tests must provide a current DRES letter to the course director and their instructor immediately. Specific arrangements will be made on a case-by-case basis.

		Fall 2015 ECE 340 COURSE SCHEDULE AND OUTLINE	2
Class Meeting	Date	Topic	Assigned §'s - Study from Streetman
1	M 08/24	Introduction to the course and general introduction to semiconductor electronics	Read Info Packet
2	W 08/26	General introduction to semiconductor electronics (cont'd)	
3	F 08/28	Semiconductors, crystal structure 1.1Solid-state Materials 1.2 Crystal Lattices	§'s 1.1, 1.2, Read §'s 1.3.1, 1.4
4	M 08/31	Bonding forces and energy bands in solids 3.1.1 Bonding Forces in Solids 3.1.2 Energy Bands	(Review topics in Chap. 2 from Phys. 214 as required) §'s 3.1, 3.1.1, 3.1.2,
5	W 09/02	Energy bands (cont'd) and charge carriers in semi- conductors 3.1.3 Metals, Semiconductors, and Insulators 3.2.1 Electrons and Holes	§'s 3.1.3, 3.2.1
6	F 09/04	Intrinsic material, extrinsic material 3.2.3 Intrinsic Material 3.2.4 Extrinsic Material	§'s 3.2.3, 3.2.4 HW1 Due
	M 09/07	Labor day: No Class	
7	W 09/09	Distribution functions, Fermi-Dirac statistics, Maxwell-Boltzmann statistics, and carrier concentrations 3.3.1 The Fermi level 3.3.2 Electron and Hole Concentrations at Equilibrium	§'s 3.3.1, 3.3.2
8	F 09/11	Distribution functions, Fermi-Dirac statistics, Maxwell-Boltzmann statistics, and carrier concentrations (cont'd) 3.3.1 The Fermi level 3.3.2 Electron and Hole Concentrations at Equilibrium	§'s 3.3.1, 3.3.2 HW2 Due
9	M 09/14	Carrier concentrations (Cont'd) and the Temperature dependence 3.3.3 Temperature Dependence of Carrier Concentrations 3.3.4 Compensation and Space Charge Neutrality	§'s 3.3.3, 3.3.4
10	W 09/16	Drift of carriers in electric fields 3.4.1 Conductivity and Mobility	§'s 3.4.1
11	F 09/18	Resistance, Temperature, impurity concentration, 3.4.2 Drift and Resistance 3.4.3 Effects of Temperature and Doping on Mobility	§'s 3.4.2, 3.4.3, HW3 Due
12	M 09/21	Invariance of the Fermi level at equilibrium 3.5 Invariance of the Fermi level at equilibrium	§'s 3.5
13	W 09/23	Optical absorption and luminescence / Carrier Generation and Recombination 4.1 Optical Absorption 4.3.1 Direct Recombination of Electrons and Holes	§'s 4.1, 4.3.1

14	F 09/25	Carrier Generation and Recombination (Cont'd) 4.3.1 Direct Recombination of Electrons and Holes 4.3.3 Steady State Carrier Generation; Quasi-Fermi Lev-	§'s 4.3.1, 4.3.3 HW4 Due
15	M 09/28	els Carrier Generation and Recombination (Cont'd) and	§'s 4.3.3, 4.3.4
		<pre>photo-conductivity 4.3.3 Steady State Carrier Generation; Quasi-Fermi Lev- els</pre>	
		4.3.4 Photoconductive Devices	
16	W 09/30	Diffusion of carriers 4.4.1 Diffusion Processes 4.4.2 Diffusion and Drift of Carriers	§'s 4.4, 4.4.1, 4.4.2
17	F 10/02	Diffusion of carriers (cont'd) 4.4.2 Diffusion and Drift of Carriers; Built-in Fields 4.4.3 Diffusion and Recombination;	§'s 4.4.2, 4.4.3 HW5 Due
18	M 10/05	Steady state carrier injection; diffusion length 4.4.4 Steady State Carrier Injection; Diffusion Length	§'s 4.4.4
19	W 10/07	Review, discussion and problem solving	
	Th 10/08	HOUR EXAM (Chaps. 1, 3, & 4, up to 4.4.2 included) 7:00 - 8:00 P.M. combined sections	
20	F 10/09	p-n junctions in equilibrium, contact potential 5.1 Fabrication of p-n Junctions, (short intro) 5.2 Equilibrium Condition 5.2.1 The Contact Potential	Read § 5.1 Study §'s 5.2, 5.2.1, 5.2.2
21	M 10/12	p-n junctions in equilibrium, space charge 5.2.2 Equilibrium Fermi Levels 5.2.3 Space Charge at a Junction	Study §'s 5.2, 5.2.1, 5.2.2, 5.2.3
22	W 10/14	Space charge at a junction 5.2.3 Space Charge at a Junction	§ 5.2.3
23	F 10/16	Current flow in a P-N junction 5.3. Forward- and Reverse-Biased Junctions; Steady State Conditions 5.3.1 Qualitative Description of Current Flow at a Junction	§ 5.2.3, 5.3, 5.3.1 HW6 Due
24	M 10/19	Carrier injection, the diode equation 5.3.2 Carrier Injection	§ 5.3.2
25	W 10/21	Minority and majority carrier currents 5.3.2 Carrier Injection 5.3.3 Reverse Bias	§'s 5.3.2, 5.3.3
26	F 10/23	Reverse-bias breakdown 5.4 Reverse-Bias Breakdown 5.4.1 Zener Breakdown 5.4.2 Avalanche Breakdown	§'s 5.4, 5.4.1, 5.4.2 HW7 Due
27	M 10/26	Stored charges, diffusion capacitance and junction capacitance 5.5.4 Capacitance of p-n Junctions	§'s 5.5.4

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28	W 10/28	Optoelectronic Devices (Photodiodes)	§'s 8.1.1, 8.1.2, 8.1.3
		8.1.1 Current and Voltage in an Illuminated Junction	
		8.1.2 Solar Cells	
		8.1.3 Photodetectors	
29	F 10/30	Optoelectronic devices (cont'd)	§'s 8.2.1, 8.2.2, 8.3, 8.4.1,
		8.2 Light-Emitting Diodes	8.4.2, 8.4.3, 8.4.4, 8.4.5
		8.4 Semiconductor Lasers	HW8 Due
30	M 11/02	Metal semiconductor junctions	§'s 5.7.1, 5.7.2, 5.7.3
		5.7.1 Schottky Barrier	
		5.7.2 Rectifying Contacts	
		5.7.3 Ohmic Contacts	
31	W 11/04	Review, discussion and problem solving	
	Th 11/05	HOUR EXAM (Chaps. 4 .4, 5 & 8) 7:00 - 8:00 PM	
		combined sections	
	F 11/06	No class	
32	M 11/09	Metal-insulator-semiconductor FET	§'s 6.4.1, 6.4.2
		6.4.1 Basic Operation	
		Metal-insulator-semiconductor FET (Cont'd)	
		6.4.2 The Ideal MOS Capacitor	
33	W 11/11	MOS Capacitor	§'s 6.4.3, 6.4.4
		6.4.3 Flatband voltage	
		6.4.4 Threshold Voltage	
34	F 11/13	MOS Capacitor (Cont'd)	§'s 6.4.5
		6.4.5 MOS Capacitance-Voltage Analysis	HW9 Due
35	M 11/16	MOS field-effect transistor	§'s 6.5.1, 6.5.2
		6.5.1 Output Characteristics	,
		6.5.2 Transfer Characteristics	
36	W 11/18	MOSFET (Cont'd):	§'s 6.5.8, 9.3.1, 9.5.1
		Small-signal analysis	
		Resistive load-NMOSFET-common-source amplifier	
		CMOS inverter (Integrated Circuits)	
37	F 11/20	Narrow-base Diode	§'s handout on BJT
		Handout on narrow-base diode	HW10 Due
	11/23-27	Thanksgiving: No Class	
38	M 11/30	Introduction to bipolar junction transistor	§'s 6.1.1, 6.1.2, 7.1, 7.2,
		BJT Fundamentals	7.3 and handout
		Relationship between narrow-based diode and BJT	
39	W 12/02	Introduction to bipolar junction transistor	§'s 7.3, 7.4.1, 7.4.2, 7.4.3,
		BJT specifics	7.4.4 and handout
40	F 12/04	Introduction to bipolar junction transistor (cont'd)	§'s 7.3, 7.4.1, 7.4.2, 7.4.3,
_		Normal mode operation	7.4.4 and handout
		1	HW11 Due
41	M 12/07	Bipolar junction transistor (Cont'd),	§'s 7.4.1, 7.4.2, 7.4.3,
		Common-emitter amplifier and small-signal current gain	7.4.4 and handout
42	W 12/09	Review, discussion and problem solving	and mildout
12	11 12/07	FINAL EXAM, (Chaps. 1, 3, 4, 5, 6, 7 & 8)	Date TBD
		1 11 1/1 12/1/11/11, (Chaps. 1, 3, 7, 3, 0, 7 & 0)	Date IDD